# WESTCODE

Date:- 2 Nov, 2001

Data Sheet Issue:- 1

# Fast Recovery Diode Types M1583VC400 to M1583VC450

# Absolute Maximum Ratings

	VOLTAGE RATINGS	MAXIMUM LIMITS	UNITS
V <sub>RRM</sub>	Repetitive peak reverse voltage, (note 1)	4000-4500	V
V <sub>RSM</sub>	Non-repetitive peak reverse voltage, (note 1)	4100-4600	V

	OTHER RATINGS (note 6)	MAXIMUM LIMITS	UNITS
I <sub>F(AV)</sub>	Mean forward current, T <sub>sink</sub> =55°C, (note 2)	1583	А
I <sub>F(AV)</sub>	Mean forward current. T <sub>sink</sub> =100°C, (note 2)	1030	А
I <sub>F(AV)</sub>	Mean forward current. T <sub>sink</sub> =100°C, (note 3)	624	А
I <sub>F(RMS)</sub>	Nominal RMS forward current, T <sub>sink</sub> =25°C, (note 2)	2963	А
I <sub>F(d.c.)</sub>	D.C. forward current, T <sub>sink</sub> =25°C, (note 4)	2569	А
I <sub>FSM</sub>	Peak non-repetitive surge $t_p=10ms$ , $V_{RM}=0.6V_{RRM}$ , (note 5)	24.8	kA
I <sub>FSM2</sub>	Peak non-repetitive surge $t_p=10ms$ , $V_{RM}\leq10V$ , (note 5)	27.3	kA
l <sup>2</sup> t	$I^{2}$ t capacity for fusing t <sub>p</sub> =10ms, V <sub>RM</sub> =0.6V <sub>RRM</sub> , (note 5)	3.08×10 <sup>6</sup>	A <sup>2</sup> s
l <sup>2</sup> t	$I^{2}t$ capacity for fusing $t_{p}$ =10ms, $V_{RM}$ ≤10V, (note 5)	3.73×10 <sup>6</sup>	A <sup>2</sup> s
T <sub>HS</sub>	Operating temperature range	-40 to +150	°C
T <sub>stg</sub>	Storage temperature range	-40 to +150	°C

Notes:-

- 1) De-rating factor of 0.13% per °C is applicable for  $T_{j}$  below 25°C.
- 2) Double side cooled, single phase; 50Hz, 180° half-sinewave.
- 3) Single side cooled, single phase; 50Hz, 180° half-sinewave.

4) Double side cooled.

5) Half-sinewave,  $150^{\circ}C T_{j}$  initial.

### **Characteristics**

	PARAMETER	MIN.	TYP.	MAX.	TEST CONDITIONS (Note 1)	UNITS
V <sub>FM</sub>	Maximum peak forward voltage	-	-	2.8	I <sub>FM</sub> =2000A	V
Vo	Threshold voltage	-	-	1.693		V
r <sub>s</sub>	Slope resistance	-	-	0.525		mΩ
V <sub>FRM</sub> Maximum		-	-	110	di/dt = 1000A/µs	V
	Maximum forward recovery voltage	-	-	70	di/dt = 1000A/µs, Tj=25°C	
I <sub>RRM</sub>	Peak reverse current	-	-	150	Rated V <sub>RRM</sub>	mA
Q <sub>rr</sub>	Reverse Recovery Charge	-	2000	-		μC
Q <sub>ra</sub>	Recovered charge, 50% Chord	-	1100	1500	I <sub>FM</sub> =1000A, t <sub>p</sub> =500µs, di/dt=200A/µs,	μC
Irm	Reverse Recovery Current	-	500	-	V <sub>r</sub> =50V, 50% Chord.	Α
t <sub>rr</sub>	Reverse recovery time, 50% Chord	-	5.0	-		μs
R	Thormal registance, junction to heatsink	-	-	0.016	Double side cooled	KAN
`th(j-hs)	mermai resistance, junction to neatsink	-	-	0.032	Single side cooled	TV VV
F	Mounting force	27	-	34		kN
Wt	Weight	-	1000	-		g

#### Notes:-

1) Unless otherwise indicated  $T_j=150$  °C.

#### **Introduction**

The M1583VC400-450 fast recovery diode range has controlled reverse recovery characteristics.

Devices with a suffix code (2 letter or letter/digit/letter combination) added to their generic code are not necessarily subject to the conditions and limits contained in this report.

#### Notes on Ratings and Characteristics

# 1.0 Voltage Grade Table

Voltage Grade	V <sub>RRM</sub> (V)	V <sub>RSM</sub> (V)	V <sub>R</sub> dc (V)
40	4000	4100	2000
42	4200	4300	2040
44	4400	4500	2080
45	4500	4600	2100

#### 2.0 De-rating Factor

A blocking voltage de-rating factor of 0.13% per °C is applicable to this device for T<sub>i</sub> below 25°C.

#### 3.0 ABCD Constants

These constants (applicable only over current range of  $V_F$  characteristic in Figure 1) are the coefficients of the expression for the forward characteristic given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

where  $I_F$  = instantaneous forward current.

#### 4.0 Reverse recovery ratings

(i)  $Q_{ra}$  is based on 50%  $I_{rm}$  chord as shown in Fig.(a) below.



(ii)  $Q_{\mbox{\scriptsize rr}}$  is based on a 150 $\mu s$  integration time.

$$Q_{rr} = \int_{0}^{150\mu s} i_{rr}.dt$$

I.e.

(iii) 
$$K \ Factor = \frac{t_1}{t_2}$$

1

#### 5.0 Reverse Recovery Loss

The following procedure is recommended for use where it is necessary to include reverse recovery loss.

From waveforms of recovery current obtained from a high frequency shunt (see Note 1) and reverse voltage present during recovery, an instantaneous reverse recovery loss waveform must be constructed. Let the area under this waveform be E joules per pulse. A new sink temperature can then be evaluated from:

$$T_{SINK} = T_{J(MAX)} - E \cdot \left[k + f \cdot R_{th(J-Hs)}\right]$$

Where k = 0.2314 (°C/W)/s

- E = Area under reverse loss waveform per pulse in joules (W.s.)
- f = Rated frequency in Hz at the original sink temperature.

 $R_{th(J-Hs)} = d.c.$  thermal resistance (°C/W)

The total dissipation is now given by:

$$W_{(tot)} = W_{(original)} + E \cdot f$$

NOTE 1 - Reverse Recovery Loss by Measurement

This device has a low reverse recovered charge and peak reverse recovery current. When measuring the charge, care must be taken to ensure that:

(a) AC coupled devices such as current transformers are not affected by prior passage of high amplitude forward current.

(b) A suitable, polarised, clipping circuit must be connected to the input of the measuring oscilloscope to avoid overloading the internal amplifiers by the relatively high amplitude forward current signal.

(c) Measurement of reverse recovery waveform should be carried out with an appropriate critically damped snubber, connected across diode anode to cathode. The formula used for the calculation of this snubber is shown below:

$$R^2 = 4 \cdot \frac{V_r}{C_s \cdot \frac{di}{dt}}$$

Where:  $V_r$  = Commutating source voltage

C<sub>S</sub> = Snubber capacitance

R = Snubber resistance

#### 6.0 Computer Modelling Parameters

6.1 Device Dissipation Calculations

$$I_{AV} = \frac{-V_o + \sqrt{V_o^2 + 4 \cdot ff^2 \cdot r_s \cdot W_{AV}}}{2 \cdot ff^2 \cdot r_s}$$

Where  $V_o = 1.693$ V,  $r_s = 0.525$ m $\Omega$ ff = form factor (normally unity for fast diode applications)

$$W_{AV} = \frac{\Delta T}{R_{th}}$$

$$\Delta T = T_{j(MAX)} - T_{Hs}$$

6.2 Calculation of  $V_F$  using ABCD Coefficients

The forward characteristic  $I_F$  Vs  $V_F$ , on Fig. 1 is represented in two ways;

- (i) the well established  $V_0$  and  $r_s$  tangent used for rating purposes and
- (ii) a set of constants A, B, C, and D forming the coefficients of the representative equation for V<sub>F</sub> in terms of I<sub>F</sub> given below:

$$V_F = A + B \cdot \ln(I_F) + C \cdot I_F + D \cdot \sqrt{I_F}$$

The constants, derived by curve fitting software, are given in this report for hot characteristics. The resulting values for  $V_F$  agree with the true device characteristic over a current range, which is limited to that plotted.

125°C Coefficients			
А	0.734962026		
В	0.04937503		
С	0.162339×10 <sup>-3</sup>		
D	0.03052379		

150°C

25°C

M1583VC400-450

Issue 1

10000

## **Curves**



#### Figure 1 – Forward characteristics of Limit device

![](_page_5_Figure_5.jpeg)

![](_page_5_Figure_6.jpeg)

Figure 4 - Recovered charge, Q<sub>ra</sub> (50% chord)

![](_page_5_Figure_8.jpeg)

# Figure 5 - Maximum reverse current, Irm

![](_page_6_Figure_3.jpeg)

![](_page_6_Figure_4.jpeg)

![](_page_6_Figure_5.jpeg)

#### Figure 6 - Maximum recovery time, t<sub>rr</sub> (50% chord)

![](_page_6_Figure_7.jpeg)

Figure 8 - Sine wave energy per pulse

![](_page_6_Figure_9.jpeg)

![](_page_7_Figure_2.jpeg)

Figure 9 - Sine wave frequency vs. pulse width

Figure 11 - Square wave frequency vs pulse width

![](_page_7_Figure_5.jpeg)

![](_page_7_Figure_6.jpeg)

Figure 10 - Sine wave frequency vs. pulse width

Figure 12 - Square wave frequency vs pulse width

![](_page_7_Figure_9.jpeg)

![](_page_8_Figure_2.jpeg)

Figure 13 - Square wave frequency vs pulse width

![](_page_8_Figure_4.jpeg)

![](_page_8_Figure_5.jpeg)

![](_page_8_Figure_6.jpeg)

Figure 16 - Square wave energy per pulse

![](_page_8_Figure_8.jpeg)

# Figure 14 - Square wave frequency vs pulse width

![](_page_9_Figure_2.jpeg)

![](_page_9_Figure_3.jpeg)

Figure 18 – Transient thermal impedance

![](_page_9_Figure_5.jpeg)

#### **Outline Drawing & Ordering Information**

![](_page_10_Figure_3.jpeg)